

## NCEP1278-VB Datasheet N-Channel 100-V (D-S) 175 °C MOSFET

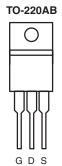
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	100			
$R_{DS(on)} (\Omega)$ at $V_{GS} = 10 V$	0.009			
$R_{DS(on)} (\Omega)$ at $V_{GS} = 4.5 V$	0. 020			
I <sub>D</sub> (A)	100			
Configuration	Single			

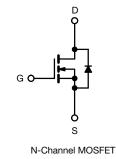
#### FEATURES

• TrenchFET<sup>®</sup> Power MOSFET



175 °C Maximum Junction Temperature
Compliant to RoHS Directive 2002/95/EC





<b>ABSOLUTE MAXIMUM RATINGS</b> $T_A = 25 \text{ °C}$ , unless otherwise noted					
Parameter			Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	100	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 25 °C	I <sub>D</sub>	100	А	
	T <sub>C</sub> = 125 °C		75 <sup>a</sup>		
Pulsed Drain Current	I <sub>DM</sub>	300	A		
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	75		
Single Pulse Avalanche Energy <sup>b</sup>	L = 0.1 mm	E <sub>AS</sub>	280	mJ	
Maximum Power Dissipation <sup>b</sup>	$T_{C}$ = 25 °C (TO-220AB and TO-263)	PD	250 <sup>c</sup>	W	
	T <sub>A</sub> = 25 °C (TO-263) <sup>d</sup>	Ū	3.75	vv	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS				
Parameter		Symbol	Limit	Unit
Junction-to-Ambient	PCB Mount (TO-263) <sup>d</sup>	R <sub>thJA</sub>	40	°C/W
Junction-to-Ambient	Free Air (TO-220AB)	''thJA	62.5	
Junction-to-Case		R <sub>thJC</sub>	0.6	

Notes:

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Gate-Source Charge<sup>c</sup>

Gate-Drain Charge<sup>c</sup>

Turn-On Delay Time<sup>c</sup>

Turn-Off DelayTime<sup>c</sup>

**Continuous Current** 

**Pulsed Current** 

Forward Voltage<sup>a</sup> **Reverse Recovery Time** 

Rise Time<sup>c</sup>

Fall Time<sup>c</sup>

NCEP1278-VB						B <sup>®</sup> VBser	
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<b>SPECIFICATIONS</b> $T_J = 25 \text{ °C}$ Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$	100				
Gate-Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	2		4	V	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1		
		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 ^{\circ}\text{C}$			50	μΑ	
		$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 175 ^{\circ}\text{C}$			250		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} = \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			А	
	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A		0.009			
Drain-Source On-State Resistance <sup>a</sup>		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 20 \text{ A}$		0.020		0	
		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 30 \text{ A}, \text{ T}_{J} = 125 ^{\circ}\text{C}$		0.023		Ω	
		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 30 \text{ A}, \text{ T}_{J} = 175 ^{\circ}\text{C}$		0.030		1	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A	25			S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			4700			
Output Capacitance	C <sub>oss</sub>	$V_{GS}$ = 0 V, $V_{DS}$ = 25 V, f = 1 MHz		665		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	]		265			
Total Gate Charge <sup>c</sup>	Qg			105	160		

17

23

12

90

55

130

1.0

85

4.5

0.17

25

135

85

195

85

240

1.5

140

7

0.35

nC

ns

А

v

ns

А

μC

Notes:

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

Source-Drain Diode Ratings and Characteristics  $T_C$  = 25  $^\circ C^b$ 

c. Independent of operating temperature.

Peak Reverse Recovery Current

Reverse Recovery Charge

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

 $V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 85 \text{ A}$ 

 $V_{DD}$  = 50 V,  $R_L$  = 0.6  $\Omega$ 

 $I_D \cong$  85 A,  $V_{GEN}$  = 10 V,  $R_q$  = 2.5  $\Omega$ 

 $I_{F} = 85 \text{ A}, V_{GS} = 0 \text{ V}$ 

 $I_{F} = 50 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}$ 

Q<sub>gs</sub>

Q<sub>gd</sub>

t<sub>d(on)</sub>

t<sub>r</sub>

t<sub>d(off)</sub>

t<sub>f</sub>

Is

I<sub>SM</sub>

V<sub>SD</sub>

t<sub>rr</sub>

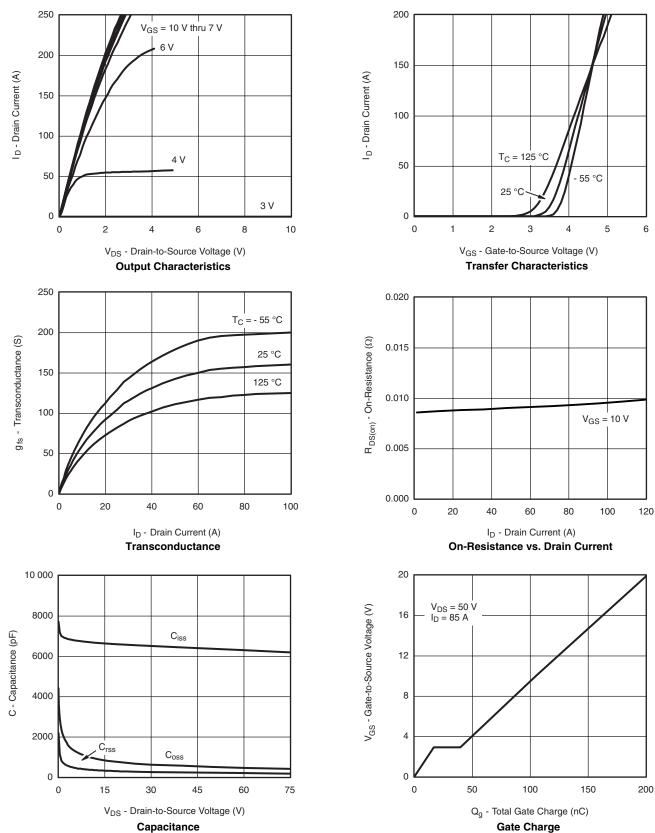
I<sub>RM(REC)</sub>

Q<sub>rr</sub>



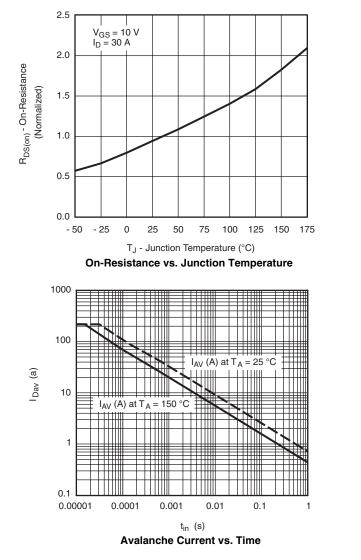
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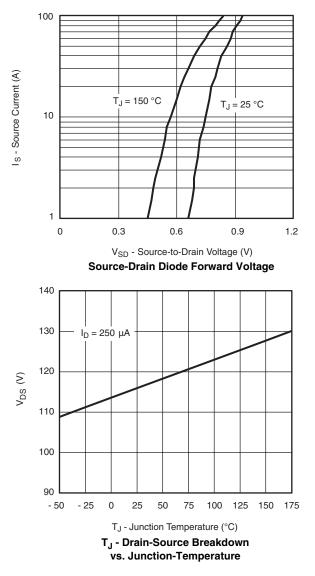
### **TYPICAL CHARACTERISTICS** $T_A = 25 \text{ °C}$ , unless otherwise noted





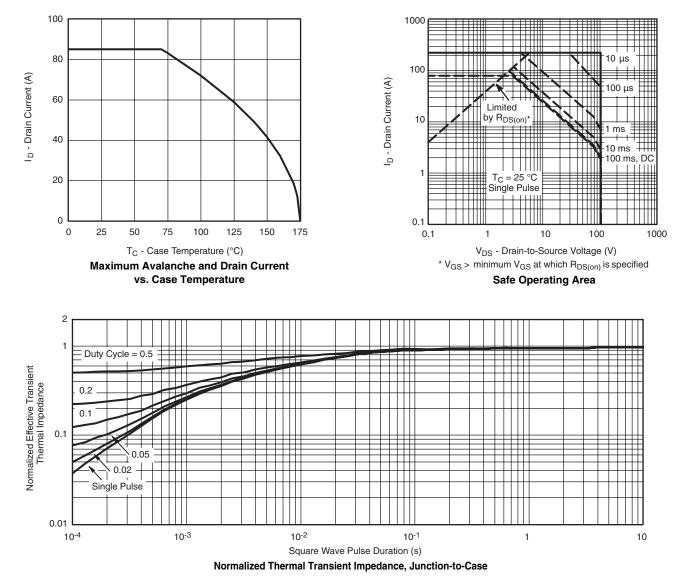
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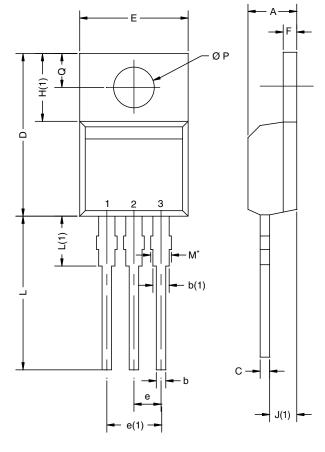


#### THERMAL RATINGS





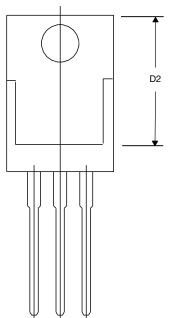
## **TO-220AB**



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
D2	12.19	12.70	0.480	0.500	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: T14-0413-Rev. P, 16-Jun-14 DWG: 5471					

#### Note

\* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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